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IN THE ABSTRACT:

The abstract of the disclosure has been amended as follows:

An event based test system having an improved characterization tool for semiconductor device testing. The characterization map provides ~~multi-dimensional~~ three-dimensional views of device performance for debug of the design, and identification of performance weaknesses. The characterization map tool exploits the capabilities of the event based test system. The ~~multi-dimensional~~ three-dimensional views include a checkerboard map such as displaying pins versus time, a shmoo plot showing pass-fail boundary points relative to predetermined parameters, or a margin map showing a pass/fail range for pins corresponding with timing changes in one or more events.